

“Measurement of the size of embedded metal clusters by mass spectrometry, transmission electron microscopy, and small-angle X-ray scattering”. Hendrich C, Favre L, Ievlev DN, Dobrynin AN, Bras W, Hörmann U, Piscopiello E, Van Tendeloo G, Lievens P, Temst K, *Applied physics A : materials science & processing* **86**, 533 (2007).
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